# DISCRETE SEMICONDUCTORS

# DATA SHEET

# MAC223 series Triacs

**Product specification** 

July 2001



Triacs MAC223 series

# **GENERAL DESCRIPTION**

Passivated triacs in a plastic envelope, intended for use in applications requiring high bidirectional transient and blocking voltage capability and high thermal cycling performance. Typical applications include motor control, industrial and domestic lighting, heating and static switching.

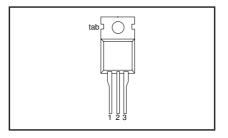
# **QUICK REFERENCE DATA**

SYMBOL	PARAMETER	MAX	MAX.	UNIT
	MAC223	A6	A8	
V <sub>DRM</sub>	Repetitive peak off-state voltages	400	600	V
I <sub>T(RMS)</sub> I <sub>TSM</sub>	RMS on-state current Non-repetitive peak on-state current	25 230	25 230	A A

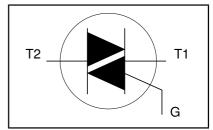
# **PINNING - TO220AB**

PIN	DESCRIPTION		
1	main terminal 1		
2	main terminal 2		
3	gate		
tab	main terminal 2		

# **PIN CONFIGURATION**



#### **SYMBOL**



# LIMITING VALUES

Limiting values in accordance with the Absolute Maximum System (IEC 134).

SYMBOL	PARAMETER	CONDITIONS		MAX.		UNIT
		MAC223		A6	A8	
$V_{DRM}$	Repetitive peak off-state voltages		-	400¹	600¹	V
I <sub>T(RMS)</sub> I <sub>TSM</sub>	RMS on-state current Non-repetitive peak on-state current	full sine wave; $T_{mb} \le 91  ^{\circ}C$ full sine wave; $T_{j} = 25  ^{\circ}C$ prior to surge	-		5	A
		t = 20 ms t = 16.7 ms	-		90 30	A A A <sup>2</sup> s
$I^2t$ $dI_T/dt$	I <sup>2</sup> t for fusing Repetitive rate of rise of on-state current after	t = 10  ms $I_{TM} = 30 \text{ A}; I_{G} = 0.2 \text{ A};$ $dI_{G}/dt = 0.2 \text{ A}/\mu\text{s}$	-		30	A <sup>2</sup> s
	triggering	T2+ G+ T2+ G- T2- G-	- - -	5 5	0 0 0	A/μs A/μs A/μs
I <sub>GM</sub> V <sub>GM</sub> P <sub>GM</sub>	Peak gate current Peak gate voltage Peak gate power	T2- G+	- - -	1 2	0 2 5	A/μs A V W
	Average gate power Storage temperature Operating junction temperature	over any 20 ms period	-40 -	0 1	.5 50 25	, C , C

<sup>1</sup> Although not recommended, off-state voltages up to 800V may be applied without damage, but the triac may switch to the on-state. The rate of rise of current should not exceed 15 A/ $\mu$ s.

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# THERMAL RESISTANCES

SYMBOL	PARAMETER	CONDITIONS	MIN.	TYP.	MAX.	UNIT
R <sub>th i-a</sub>	Thermal resistance junction to mounting base Thermal resistance junction to ambient	full cycle half cycle in free air		- - 60	1.0 1.4 -	K/W K/W K/W

# STATIC CHARACTERISTICS

T<sub>i</sub> = 25 °C unless otherwise stated

SYMBOL	PARAMETER	CONDITIONS		MIN.	TYP.	MAX.	UNIT
I <sub>GT</sub>	Gate trigger current	$V_D = 12 \text{ V}; I_T = 0.1 \text{ A}$					
		T24	+ G+	-	6	50	mA
		· - ·	+ G-	-	10	50	mA
			- G-	-	11	50	mA
1,	Latching current	$V_D = 12 \text{ V}; I_{GT} = 0.1 \text{ A}$	- G+	-	23	75	mA
<sup>1</sup> L	Latering current		+ G+	_	8	40	mA
			+ G-	-	30	60	mA
			- G-	-	18	40	mA
			- G+	-	15	60	mA
I <sub>H</sub>	Holding current	$V_D = 12 \text{ V}; I_{GT} = 0.1 \text{ A}$			_		_
		T2-		-	7	30	mA
\ , ,	On atata walta sa	T2-	-	-	12	30	mΑ
$V_{T}$	On-state voltage Gate trigger voltage	$\begin{vmatrix} I_T = 30 \text{ A} \\ V_D = 12 \text{ V}; I_T = 0.1 \text{ A} \end{vmatrix}$		-	1.3 0.7	1.55 1.5	V V
V <sub>GT</sub>	Gate trigger voltage	$V_D = 12 \text{ V}, I_T = 0.1 \text{ A}$ $V_D = 400 \text{ V}; I_T = 0.1 \text{ A}; T_i = 125 ^{\circ}\text{C}$		0.25	0.7	1.5	V
I <sub>D</sub>	Off-state leakage current	$V_{D} = V_{DRM(max)}$ ; $T_{j} = 125 \text{ °C}$		-	0.1	0.5	mΑ

# **DYNAMIC CHARACTERISTICS**

 $T_i = 25$  °C unless otherwise stated

SYMBOL	PARAMETER	CONDITIONS	MIN.	TYP.	MAX.	UNIT
dV <sub>D</sub> /dt	Critical rate of rise of	$V_{DM} = 67\% V_{DRM(max)}; T_j = 125 °C;$	100	300	-	V/μs
dV <sub>com</sub> /dt	off-state voltage Critical rate of change of commutating voltage	exponential waveform; gate open circuit $V_{DM} = 400 \text{ V}$ ; $T_j = 95 \text{ °C}$ ; $I_{T(RMS)} = 25 \text{ A}$ ; $dI_{com}/dt = 9 \text{ A/ms}$ ; gate open circuit	-	10	-	V/μs
t <sub>gt</sub>	Gate controlled turn-on time	$I_{TM} = 30 \text{ A}; V_D = V_{DRM(max)}; I_G = 0.1 \text{ A};$ $I_{G} = 5 \text{ A}/\mu \text{s}$	-	2	-	μs

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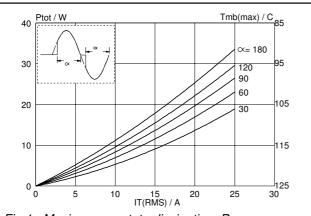


Fig.1. Maximum on-state dissipation,  $P_{tot}$ , versus rms on-state current,  $I_{T(RMS)}$ , where  $\alpha$  = conduction angle.

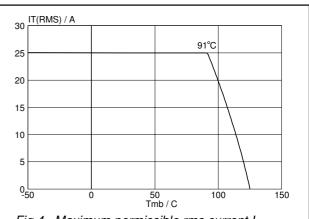


Fig.4. Maximum permissible rms current  $I_{T(RMS)}$ , versus mounting base temperature  $T_{mb}$ .

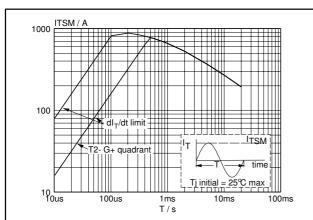


Fig.2. Maximum permissible non-repetitive peak on-state current  $l_{TSM}$ , versus pulse width  $t_p$ , for sinusoidal currents,  $t_p \le 20$ ms.

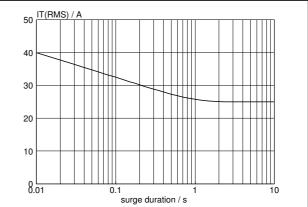


Fig.5. Maximum permissible repetitive rms on-state current  $I_{T(RMS)}$ , versus surge duration, for sinusoidal currents, f = 50 Hz;  $T_{mb} \le 91$  °C.

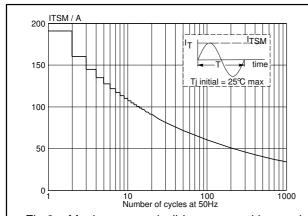


Fig.3. Maximum permissible non-repetitive peak on-state current  $I_{\text{TSM}}$ , versus number of cycles, for sinusoidal currents, f = 50 Hz.

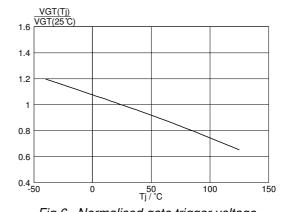
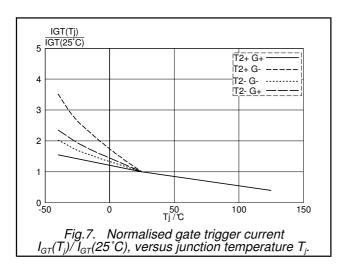
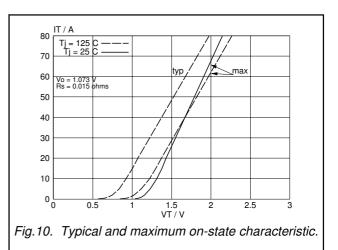
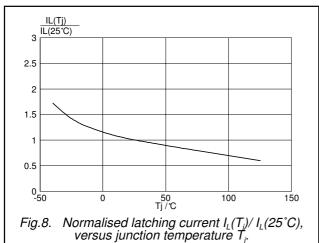


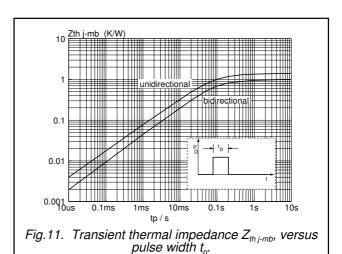
Fig.6. Normalised gate trigger voltage  $V_{\rm GT}(T_{\rm j})/V_{\rm GT}(25\,^{\circ}{\rm C})$ , versus junction temperature  $T_{\rm j}$ .

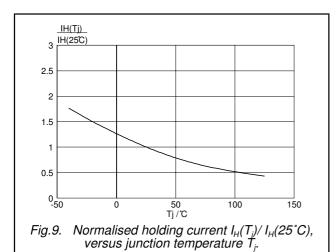
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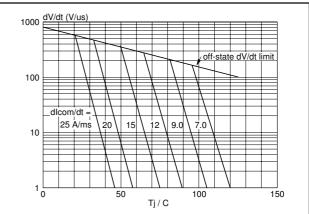
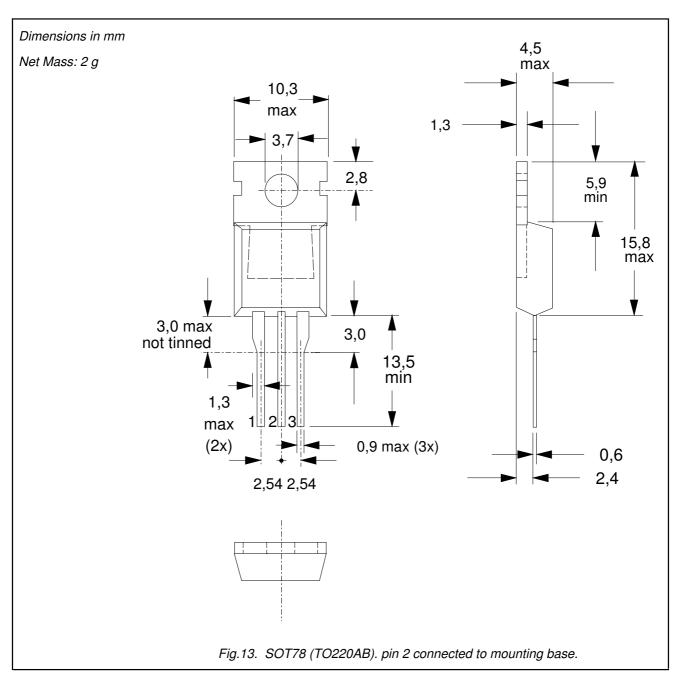


Fig. 12. Typical commutation dV/dt versus junction temperature, parameter commutation  $dI_{\tau}/dt$ . The triac should commutate when the dV/dt is below the value on the appropriate curve for pre-commutation  $dI_{\tau}/dt$ .

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# **Notes**

- Refer to mounting instructions for SOT78 (TO220) envelopes.
   Epoxy meets UL94 V0 at 1/8".

# Legal information

#### **DATA SHEET STATUS**

DOCUMENT STATUS <sup>(1)</sup>	PRODUCT STATUS <sup>(2)</sup>	DEFINITION
Objective data sheet	Development	This document contains data from the objective specification for product development.
Preliminary data sheet	Qualification	This document contains data from the preliminary specification.
Product data sheet	Production	This document contains the product specification.

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